Fu-Kwun Wang

List of Publications by Year
in descending order

148 papers	3,458 citations	159525 30 h-index	175177 52 g-index
148 all docs	148 docs citations	148 times ranked	2277 citing authors

#	Article	IF	Citations
1	A Deep convolutional neural network with residual blocks for wafer map defect pattern recognition. Quality and Reliability Engineering International, 2022, 38, 343-357.	1.4	8
2	A hybrid method for online cycle life prediction of lithiumâ€ion batteries. International Journal of Energy Research, 2022, 46, 9080-9096.	2.2	11
3	Online remaining useful life prediction of lithium-ion batteries using bidirectional long short-term memory with attention mechanism. Energy, 2022, 254, 124344.	4.5	46
4	Ensemble model for the degradation prediction of proton exchange membrane fuel cell stacks. Quality and Reliability Engineering International, 2021, 37, 34-46.	1.4	10
5	A Hybrid Method for Remaining Useful Life Prediction of Proton Exchange Membrane Fuel Cell Stack. IEEE Access, 2021, 9, 40486-40495.	2.6	8
6	Attention-Based Long Short-Term Memory Recurrent Neural Network for Capacity Degradation of Lithium-Ion Batteries. Batteries, 2021, 7, 66.	2.1	7
7	Integrating quality function deployment and failure mode and effect analysis in subcontractor selection. Total Quality Management and Business Excellence, 2020, 31, 697-716.	2.4	8
8	Exponentially weighted moving average chart with a likelihood ratio test for monitoring autocorrelated processes. Quality and Reliability Engineering International, 2020, 36, 753-764.	1.4	8
9	Stacked long short-term memory model for proton exchange membrane fuel cell systems degradation. Journal of Power Sources, 2020, 448, 227591.	4.0	44
10	Ensemble Model Based on Stacked Long Short-Term Memory Model for Cycle Life Prediction of Lithiumâ€"Ion Batteries. Applied Sciences (Switzerland), 2020, 10, 3549.	1.3	11
11	Long Short-Term Memory With Attention Mechanism for State of Charge Estimation of Lithium-Ion Batteries. IEEE Access, 2020, 8, 94140-94151.	2.6	33
12	Gradient boosted regression model for the degradation analysis of prismatic cells. Computers and Industrial Engineering, 2020, 144, 106494.	3.4	29
13	Bi-directional long short-term memory recurrent neural network with attention for stack voltage degradation from proton exchange membrane fuel cells. Journal of Power Sources, 2020, 461, 228170.	4.0	56
14	Hybrid approach for remaining useful life prediction of ball bearings. Quality and Reliability Engineering International, 2019, 35, 2494-2505.	1.4	28
15	Acceptance sampling plans based on EWMA yield index for the first order autoregressive process. Journal of the Operational Research Society, 2019, 70, 1179-1192.	2.1	5
16	A double exponentially weighted moving average chart based on likelihood ratio for monitoring an inflated Pareto process. Quality and Reliability Engineering International, 2019, 35, 1698-1715.	1.4	2
17	Oneâ€sided control chart based on support vector machines with differential evolution algorithm. Quality and Reliability Engineering International, 2019, 35, 1634-1645.	1.4	15
18	Selecting better process based on difference statistic using double sampling plan. Communications in Statistics - Theory and Methods, 2019, 48, 2641-2656.	0.6	4

#	Article	IF	Citations
19	Comparison of different control charts for a Weibull process with type-I censoring. Communications in Statistics Part B: Simulation and Computation, 2019, 48, 1088-1100.	0.6	9
20	EWMA chart based on Bayesâ€conditional pivotal quantity for Weibull percentiles under complete data and typeâ€II censoring. Quality and Reliability Engineering International, 2018, 34, 707-717.	1.4	1
21	VSSI median control chart with estimated parameters and measurement errors. Quality and Reliability Engineering International, 2018, 34, 867-881.	1.4	18
22	Acceptance sampling plan based on an exponentially weighted moving average statistic with the yield index for autocorrelation between polynomial profiles. Communications in Statistics - Theory and Methods, 2018, 47, 4859-4871.	0.6	6
23	New control charts for monitoring the Weibull percentiles under complete data and Typeâ€II censoring. Quality and Reliability Engineering International, 2018, 34, 403-416.	1.4	16
24	A multiple dependent state repetitive sampling plan for linear profiles. Journal of the Operational Research Society, 2018, 69, 467-473.	2.1	16
25	Sampling plans by variables for inflated-Pareto data in the food industry. Food Control, 2018, 84, 97-105.	2.8	7
26	A New Approach for Product Acceptance Determination for Multiple Manufacturing Lines. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2018, 8, 317-325.	1.4	1
27	The performance of EWMA median and CUSUM median control charts for a normal process with measurement errors. Quality and Reliability Engineering International, 2018, 34, 203-213.	1.4	21
28	Sampling plans for the zero-inflated Poisson distribution in the food industry. Food Control, 2018, 85, 359-368.	2.8	9
29	EWMA chart with variable sample size and sampling interval for monitoring Pareto data with estimated parameters. Quality and Reliability Engineering International, 2018, 34, 1775-1784.	1.4	2
30	A hybrid model based on support vector regression and differential evolution for remaining useful lifetime prediction of lithium-ion batteries. Journal of Power Sources, 2018, 401, 49-54.	4.0	91
31	Sampling plans for the zeroâ€inflated negative binomial distribution in the food industry. Quality and Reliability Engineering International, 2018, 34, 1174-1184.	1.4	2
32	Evaluation of Two Process Yields in Acceptance Sampling Plans. Journal of Testing and Evaluation, 2018, 46, 756-763.	0.4	4
33	Implementing EWMA Yield Index for Simple Linear Profiles with One-sided Specifications in Product Acceptance Determination. Quality and Reliability Engineering International, 2017, 33, 401-412.	1.4	6
34	MaxEWMA Control Chart for a Weibull Process with Individual Measurements. Quality and Reliability Engineering International, 2017, 33, 369-379.	1.4	13
35	Dependent Mixed and Mixed Repetitive Sampling Plans for Linear Profiles. Quality and Reliability Engineering International, 2017, 33, 1669-1683.	1.4	11
36	Exponentially weighted moving average control charts based on the moving average statistic and lnS² for monitoring a Weibull process with subgroups. Quality and Reliability Engineering International, 2017, 33, 1901-1913.	1.4	1

#	Article	IF	Citations
37	An exponentially weighted moving average chart based on likelihoodâ€ratio test for monitoring <scp>Weibull</scp> mean and variance with subgroups. Quality and Reliability Engineering International, 2017, 33, 2409-2421.	1.4	4
38	A comparison study of control charts for Weibull distributed time between events. Quality and Reliability Engineering International, 2017, 33, 2747-2759.	1.4	17
39	Acceptance sampling plans for linear profiles with one-sided specifications. Journal of Statistical Computation and Simulation, 2017, 87, 806-816.	0.7	11
40	Sampling Schemes by Variables Inspection for the First-Order Autoregressive Model between Linear Profiles. Mathematical Problems in Engineering, 2017, 2017, 1-11.	0.6	4
41	Single Mixed Sampling Plan Based on Yield Index for Linear Profiles. Quality and Reliability Engineering International, 2016, 32, 1535-1543.	1.4	3
42	Multiple Comparisons with the Best for Process Selection for Linear Profiles with One-sided Specifications. Quality and Reliability Engineering International, 2016, 32, 697-704.	1.4	3
43	Variables Sampling Plan for Resubmitted Lots in a Process with Linear Profiles. Quality and Reliability Engineering International, 2016, 32, 1029-1040.	1.4	16
44	Sampling Plan based on the Exponentially Weighted Moving Average Yield Index for Autocorrelation within Linear Profiles. Quality and Reliability Engineering International, 2016, 32, 1757-1768.	1.4	7
45	Process Yield Analysis for Nonlinear Profiles in the Presence of Gauge Measurement Errors. Quality and Reliability Engineering International, 2016, 32, 2435-2442.	1.4	2
46	Process yield analysis for multivariate linear profiles. Quality Technology and Quantitative Management, 2016, 13, 124-138.	1.1	12
47	Evaluating the efficiency of green vehicles and diesel vehicles. International Journal of Green Energy, 2016, 13, 1163-1174.	2.1	5
48	The Difference Test Statistic for Two Suppliers with Linear Profiles. Quality and Reliability Engineering International, 2016, 32, 69-78.	1.4	12
49	Supplier Selection for Multiple Linear Profiles with One-Sided Specifications. Quality and Reliability Engineering International, 2016, 32, 257-268.	1.4	7
50	Process Yield for Multiple Stream Processes with Individual Observations and Subsamples. Quality and Reliability Engineering International, 2016, 32, 335-344.	1.4	3
51	Implementing the Ratio Test Statistic to Compare Two Suppliers for Linear Profiles. Quality and Reliability Engineering International, 2016, 32, 1191-1203.	1.4	1
52	Two New Independent Mixed Sampling Plans for Inspecting a Product with Linear Profiles. Quality and Reliability Engineering International, 2016, 32, 2999-3009.	1.4	3
53	Using the design for Six Sigma approach with TRIZ for new product development. Computers and Industrial Engineering, 2016, 98, 522-530.	3.4	53
54	Process Yield for Multivariate Linear Profiles with One-sided Specification Limits. Quality and Reliability Engineering International, 2016, 32, 1281-1293.	1.4	10

#	Article	IF	Citations
55	A Single Sampling Plan Based on Exponentially Weighted Moving Average Model for Linear Profiles. Quality and Reliability Engineering International, 2016, 32, 1795-1805.	1.4	9
56	Multiple comparisons with the best for supplier selection with linear profiles. International Journal of Production Research, 2016, 54, 1388-1397.	4.9	11
57	Applying grey model to predict the useful lifetime for high-power white LEDs. Optical and Quantum Electronics, 2016, 48, 1.	1.5	1
58	Lower Confidence Bound for Process-Yield Index Spkwith Autocorrelated Process Data. Quality Technology and Quantitative Management, 2015, 12, 253-267.	1.1	11
59	A New Model for Repairable Systems with Nonmonotone Intensity Function. Quality and Reliability Engineering International, 2015, 31, 1553-1563.	1.4	8
60	Process Selection for Linear Profiles with Oneâ€sided Specifications Based on the Ratio Test Statistic. Quality and Reliability Engineering International, 2015, 31, 1575-1585.	1.4	9
61	Measuring the Process Yield for Circular Profiles. Quality and Reliability Engineering International, 2015, 31, 579-588.	1.4	8
62	An extended optimal replacement model for a deteriorating system with inspections. Reliability Engineering and System Safety, 2015, 139, 33-49.	5.1	20
63	Process Yield Analysis for Linear Withinâ€Profile Autocorrelation. Quality and Reliability Engineering International, 2015, 31, 1053-1061.	1.4	9
64	Useful lifetime of white OLED under a constant stress accelerated life testing. Optical and Quantum Electronics, 2015, 47, 323-329.	1.5	7
65	Implementing particle swarm optimization algorithm to estimate the mixture of two Weibull parameters with censored data. Journal of Statistical Computation and Simulation, 2014, 84, 1975-1989.	0.7	23
66	A new bounded intensity function for repairable systems. Journal of Industrial and Production Engineering, 2014, 31, 36-40.	2.1	1
67	Applying a Hybrid MCDM Model for Six Sigma Project Selection. Mathematical Problems in Engineering, 2014, 2014, 1-13.	0.6	17
68	A New Decision Model for Reducing Trim Loss and Inventory in the Paper Industry. Journal of Applied Mathematics, 2014, 2014, 1-10.	0.4	1
69	Flexible Stock Allocation and Trim Loss Control for Cutting Problem in the Industrial-Use Paper Production. Mathematical Problems in Engineering, 2014, 2014, 1-9.	0.6	1
70	A Process Yield for Simple Linear Profiles. Quality Engineering, 2014, 26, 311-318.	0.7	29
71	Measuring Process Yield for Nonlinear Profiles. Quality and Reliability Engineering International, 2014, 30, 1333-1339.	1.4	31
72	Measuring the Process Yield for Simple Linear Profiles with oneâ€sided Specification. Quality and Reliability Engineering International, 2014, 30, 1145-1151.	1.4	23

#	Article	IF	Citations
73	Evaluating Management Consultants for Six Sigma Projects. Arabian Journal for Science and Engineering, 2014, 39, 2371-2379.	1.1	5
74	Useful lifetime analysis for high-power white LEDs. Microelectronics Reliability, 2014, 54, 1307-1315.	0.9	53
75	Process yield analysis for autocorrelation between linear profiles. Computers and Industrial Engineering, 2014, 71, 50-56.	3.4	24
76	Using BBPSO Algorithm to Estimate the Weibull Parameters with Censored Data. Communications in Statistics Part B: Simulation and Computation, 2014, 43, 2614-2627.	0.6	11
77	M-estimator for estimating the Burr type III parameters with outliers. Mathematics and Computers in Simulation, 2014, 105, 144-159.	2.4	2
78	A Comparison Study of Replenishment Strategies in Vendor-Managed Inventory. Arabian Journal for Science and Engineering, 2014, 39, 5253-5264.	1.1	2
79	Implementing support vector regression with differential evolution to forecast motherboard shipments. Expert Systems With Applications, 2014, 41, 3850-3855.	4.4	18
80	New Reliability Model in the Development Phase of a System. Quality Technology and Quantitative Management, 2014, 11, 297-306.	1.1	1
81	Defect Prediction for New Products During the Development Phase. Journal of Testing and Evaluation, 2014, 42, 989-995.	0.4	1
82	Implementing a diffusion model optimized by a hybrid evolutionary algorithm to forecast notebook shipments. Applied Soft Computing Journal, 2013, 13, 1147-1151.	4.1	8
83	Process Yield for a Manufactured Product. Quality Technology and Quantitative Management, 2013, 10, 483-494.	1.1	6
84	An Assessment of Gauge Repeatability and Reproducibility with Multiple Characteristics. Journal of Testing and Evaluation, 2013, 41, 651-658.	0.4	4
85	Combining Diffusion and Grey Models Based on Evolutionary Optimization Algorithms to Forecast Motherboard Shipments. Mathematical Problems in Engineering, 2012, 2012, 1-10.	0.6	1
86	Estimating the Burr XII Parameters in Constant-Stress Partially Accelerated Life Tests Under Multiple Censored Data. Communications in Statistics Part B: Simulation and Computation, 2012, 41, 1711-1727.	0.6	12
87	Partially Accelerated Life Tests for the Weibull Distribution Under Multiply Censored Data. Communications in Statistics Part B: Simulation and Computation, 2012, 41, 1667-1678.	0.6	11
88	The best vendor selection for conducting the recycled material based on a hybrid MCDM model combining DANP with VIKOR. Resources, Conservation and Recycling, 2012, 66, 95-111.	5.3	180
89	Lifetime predictions of LED-based light bars by accelerated degradation test. Microelectronics Reliability, 2012, 52, 1332-1336.	0.9	77
90	Application of Lean Six Sigma to a panel equipment manufacturer. Total Quality Management and Business Excellence, 2012, 23, 417-429.	2.4	49

#	Article	IF	Citations
91	Estimating the Process Yield of Multiple Characteristics With One-Sided Specifications. IEEE Transactions on Semiconductor Manufacturing, 2012, 25, 57-62.	1.4	1
92	Confidence intervals for two-dimensional data with circular tolerances in a gauge R&R study. Quality and Quantity, 2012, 46, 55-69.	2.0	2
93	A Gauge Study for Dynamic Light Scattering and Differential Mobility Analyzer Instruments. Journal of Testing and Evaluation, 2012, 40, 580-585.	0.4	1
94	M-estimator with asymmetric influence function for estimating the Burr type III parameters with outliers. Computers and Mathematics With Applications, 2011, 62, 1896-1907.	1.4	4
95	The mean time between failures for an LCD panel. Quality and Reliability Engineering International, 2011, 27, 203-208.	1.4	3
96	Using adaptive network-based fuzzy inference system to forecast automobile sales. Expert Systems With Applications, 2011, 38, 10587-10593.	4.4	70
97	Process-oriented basis representation for a multivariate gauge study. Computers and Industrial Engineering, 2010, 58, 143-150.	3.4	29
98	Adaptive neuro-fuzzy inference system for combined forecasts in a panel manufacturer. Expert Systems With Applications, 2010, 37, 8119-8126.	4.4	10
99	EM algorithm for estimating the Burr XII parameters with multiple censored data. Quality and Reliability Engineering International, 2010, 26, 615-630.	1.4	19
100	An M-Estimator for Estimating the Extended Burr Type III Parameters with Outliers. Communications in Statistics - Theory and Methods, 2010, 40, 304-322.	0.6	5
101	Applying Lean Six Sigma and TRIZ methodology in banking services. Total Quality Management and Business Excellence, 2010, 21, 301-315.	2.4	101
102	A General Procedure for Process Yield With Multiple Characteristics. IEEE Transactions on Semiconductor Manufacturing, 2010, 23, 503-508.	1.4	15
103	Robust regression for estimating the Burr XII parameters with outliers. Journal of Applied Statistics, 2010, 37, 807-819.	0.6	7
104	Modified diffusion model with multiple products using a hybrid GA approach. Expert Systems With Applications, 2009, 36, 12613-12620.	4.4	19
105	Applying Six Sigma methodology to collaborative forecasting. International Journal of Advanced Manufacturing Technology, 2008, 39, 1033-1044.	1.5	18
106	Applying Bootstrap method to the types Iâ€“II errors in the measurement system. Quality and Reliability Engineering International, 2008, 24, 83-97.	1.4	2
107	Forecasting for the LCD monitor market. Journal of Forecasting, 2008, 27, 341-356.	1.6	10
108	Lot release times and dispatching rule for a TFT-LCD cell process. Robotics and Computer-Integrated Manufacturing, 2008, 24, 228-238.	6.1	23

#	Article	IF	Citations
109	Process Yield With Measurement Errors in Semiconductor Manufacturing. IEEE Transactions on Semiconductor Manufacturing, 2008, 21, 279-284.	1.4	6
110	Applying Capability Index to the Supply Network Analysis. Total Quality Management and Business Excellence, 2007, 18, 425-434.	2.4	17
111	A real-time vehicle-dispatching system for consolidating milk runs. Transportation Research, Part E: Logistics and Transportation Review, 2007, 43, 565-577.	3.7	61
112	Product mix in the TFT-LCD industry. Production Planning and Control, 2007, 18, 584-591.	5.8	17
113	Multivariate Capability Indices: Distributional and Inferential Properties. Journal of Applied Statistics, 2007, 34, 941-962.	0.6	27
114	APPLYING PRINCIPAL COMPONENT ANALYSIS TO A GR&R STUDY. Journal of the Chinese Institute of Industrial Engineers, 2007, 24, 182-189.	0.5	13
115	Measuring production yield for processes with multiple quality characteristics. International Journal of Production Research, 2006, 44, 4649-4661.	4.9	29
116	Evaluating the efficiency of implementing total productive maintenance. Total Quality Management and Business Excellence, 2006, 17, 655-667.	2.4	45
117	Quality Evaluation of a Manufactured Product with Multiple Characteristics. Quality and Reliability Engineering International, 2006, 22, 225-236.	1.4	40
118	A hybrid push/pull-dispatching rule for a photobay in a 300mm wafer fab. Robotics and Computer-Integrated Manufacturing, 2006, 22, 47-55.	6.1	30
119	Analysis of the supply and demand in the TFTâ€“LCD market. Technological Forecasting and Social Change, 2006, 73, 422-435.	6.2	15
120	The performance of the number of vehicles in a dynamic connecting transport AMHS. International Journal of Production Research, 2005, 43, 2263-2276.	4.9	24
121	A simple data transformation of auto-correlated data for SPC. International Journal of Production Research, 2005, 43, 981-989.	4.9	10
122	A parameterized-dispatching rule for a Logic IC sort in a wafer fabrication. Production Planning and Control, 2005, 16, 426-436.	5.8	17
123	Applying Six-Sigma to Supplier Development. Total Quality Management and Business Excellence, 2004, 15, 1217-1229.	2.4	56
124	The maximum loading and the optimum number of vehicles in a double-loop of an interbay material handling system. Production Planning and Control, 2004, 15, 247-255.	5.8	9
125	Virtual vehicle in the connecting transport automated material-handling system (AMHS). International Journal of Production Research, 2004, 42, 2599-2610.	4.9	20
126	Capacity-constrained scheduling for a logic IC final test facility. International Journal of Production Research, 2004, 42, 79-99.	4.9	31

#	Article	IF	Citations
127	Operating Characteristic Curves for the Exponential Bayes-Truncated Test. Quality and Reliability Engineering International, 2004, 20, 337-342.	1.4	3
128	Performance evaluation of an automated material handling system for a wafer fab. Robotics and Computer-Integrated Manufacturing, 2004, 20, 91-100.	6.1	42
129	An evaluation of freight consolidation policies in global third party logistics. Omega, 2003, 31, 55-62.	3.6	123
130	Confidence intervals in repeatability and reproducibility using the Bootstrap method. Total Quality Management and Business Excellence, 2003, 14, 341-354.	2.4	21
131	Applying collaborative transportation management models in global third-party logistics. International Journal of Computer Integrated Manufacturing, 2003, 16, 283-291.	2.9	43
132	Simulation analysis of the connecting transport AMHS in a wafer fab. IEEE Transactions on Semiconductor Manufacturing, 2003, 16, 555-564.	1.4	39
133	Connecting transport AMHS in a wafer fab. International Journal of Production Research, 2003, 41, 529-544.	4.9	37
134	Development of a state-dependent dispatch rule using theory of constraints in near-real-world wafer fabrication. Production Planning and Control, 2002, 13, 253-261.	5.8	29
135	Quality Evaluation of Geometric Tolerance Regions in Form and Location. Quality Engineering, 2002, 14, 205-211.	0.7	8
136	The effect of the Bootstrap method on additive fixed data perturbation in statistical database. Omega, 2002, 30, 367-379.	3.6	1
137	Simulation analysis of dispatching rules for an automated interbay material handling system in wafer fab. International Journal of Production Research, 2001, 39, 1221-1238.	4.9	89
138	Confidence interval for the mean of non-normal data. Quality and Reliability Engineering International, 2001, 17, 257-267.	1.4	26
139	Learning curve analysis in total productive maintenance. Omega, 2001, 29, 491-499.	3.6	42
140	A new model with bathtub-shaped failure rate using an additive Burr XII distribution. Reliability Engineering and System Safety, 2000, 70, 305-312.	5.1	126
141	Using principal component analysis in process performance for multivariate data. Omega, 2000, 28, 185-194.	3.6	117
142	Comparison of Three Multivariate Process Capability Indices. Journal of Quality Technology, 2000, 32, 263-275.	1.8	91
143	CAPABILITY INDEX USING PRINCIPAL COMPONENTS ANALYSIS. Quality Engineering, 1998, 11, 21-27.	0.7	96
144	The Burr XII Distribution in Reliability Analysis. Journal of Quality Technology, 1998, 30, 386-394.	1.8	189

#	Article	IF	Citations
145	Weibull Maximum Likelihood Parameter Estimates with Censored Data. Journal of Quality Technology, 1997, 29, 105-110.	1.8	28
146	Maximum likelihood estimation of the Burr XII parameters with censored and uncensored data. Microelectronics Reliability, 1996, 36, 359-362.	0.9	55
147	Improved percentile estimation for the two-parameter Weibull distribution. Microelectronics Reliability, 1995, 35, 883-892.	0.9	20
148	Optimal number of minimal repairs before replacement of a deteriorating system with inspections. International Journal of Systems Science, 0, , 1-13.	3.7	3